

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	1	LAIWALLA ET AL.
	Examiner	Art Unit
	Ahshik Kim	2876

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,086,584	08-2006	Stoutenburg et al.	235/379
*	B	US-2003/0033252	02-2003	Buttridge et al.	705/45
*	C	US-6,149,056	11-2000	Stinson et al.	235/379
*	D	US-5,890,141	03-1999	Carney et al.	705/45
*	E	US-6,886,743	05-2005	Brikho, Ghassan	235/379
*	F	US-2004/0111371	06-2004	Friedman, Lawrence J.	705/042
*	G	US-6,354,491	03-2002	Nichols et al.	235/379
*	H	US-6,038,666	03-2000	Hsu et al.	713/186
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.